# MOSFET

600V CoolMOS™ CP Power Transistor

The CoolMOS™ CP series offers devices which provide all benefits of a fast switching SJ MOSFET while not sacrificing ease of use. Extremely low switching and conduction losses make switching applications even more efficient, more compact, lighter, and cooler..

ThinPAK

ThinPAK is a a new leadless SMD package for HV MOSFETs. The new package has a very small footprint of only 64mm² (vs. 150mm² for the D²PAK) and a very low profile with only 1mm height (vs. 4.4mm for the D²PAK). The significantly smaller package size, combined with benchmark low parasitic inductances, provides designers with a new and effective way to decrease system solution size in power-density driven designs.

ThinPAK 8x8
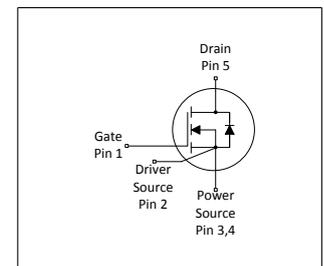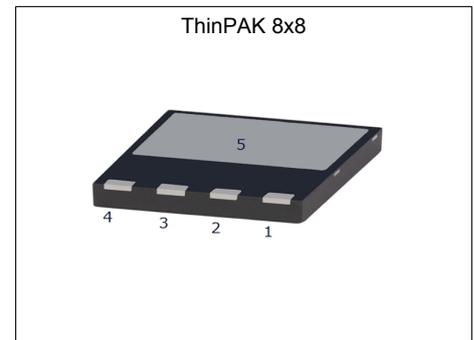
Features

• Reduced board space consumption
• Increased power density
• Short commutation loop
• Smooth switching waveform
• easy to use products
• Extremely low losses due to very low FOM Rdson*Qg and Eoss
• Quallfied according to JEDEC (J-STD20 and JESD22) for target applications (Server, Adapter)
• Pb-free plating, Halogen free

Potential applications

Server, Adapter

Table 1   Key Performance Parameters

Parameter	Value	Unit
V_{ds} @ T_{jmax}	650	V
$R_{DS(on),max}$	0.199	Ω
$Q_{g,typ}$	32	nC
$I_{D,pulse}$	63	A
E_{oss} @ 400V	6.1	µJ
Body diode di_F/dt	200	A/µs

Type / Ordering Code	Package	Marking	Related Links
IPL60R199CP	PG-VSON-4	6R199P	see Appendix A

Table of Contents

1   Maximum ratings

at T_j = 25°C, unless otherwise specified

Table 2   Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current[1]	I_D	- -	- -	16.4 10.0	A	T_C = 25°C T_C = 100°C
Pulsed drain current[2]	$I_{D,pulse}$	-	-	63	A	T_C=25 °C
Avalanche energy, single pulse	E_{AS}	-	-	436	mJ	I_D =6.6 A; V_{DD} = 50 V
Avalanche energy, repetitive[3]	E_{AR}	-	-	0.66	mJ	I_D =6.6 A; V_{DD} = 50 V
Avalanche current, repetitive[3]	I_{AR}	-	-	6.6	A	-
MOSFET dv/dt ruggedness	dv/dt	-	-	50	V/ns	V_{DS} =0...480 V
Gate source voltage	V_{GS}	-20 -30	- -	20 30	V	static; AC (f>1 Hz)
Power dissipation	P_{tot}	-	-	139	W	T_C=25 °C
Operating Temperature	T_j	-40	-	150	°C	-
Storage Temperature	T_{stg}	-40	-	125	°C	-
Continuous diode forward current	I_S	-	-	16.4	A	T_C=25 °C
Diode pulse current[2]	$I_{S,pulse}$	-	-	63	A	T_C = 25°C
Reverse diode dv/dt[4]	dv/dt	-	-	15	V/ns	V_{DS} =0...400 V, I_{SD}<= I_D, T_j=25 °C see table 8
Maximum diode commutation speed	di_F/dt	-	-	200	A/µs	V_{DS} =0...400 V, I_{SD}<= I_D, T_j=25 °C see table 8

2   Thermal characteristics

Table 3   Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	0.9	°C/W	-
Thermal resistance, junction - ambient[5]	R_{thJA}	-	-	45	°C/W	SMD version, device on PCB, 6cm² cooling area
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	reflow MSL2a

[1] Limited by $T_{j\,max}$. Maximum duty cycle
[2] Pulse width t_p limited by $T_{j,max}$
[3] Repetitive avalanche causes additional power losses that can be calculated as P_{AV}=E_{AR}*f; Pulse width t_p limited by $T_{j,max}$
[4] Identical low side and high side switch with identical R_G
[5] Device on 40mm*40mm*1.5mm one layer epoxy PCB FR4 with 6cm2 copper area (thickness 70?m) for drain connection. PCB is vertical without air stream cooling.

3 Electrical characteristics

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	600	-	-	V	V_{GS}=0 V, I_D=0.25 mA
Gate threshold voltage	$V_{(GS)th}$	2.5	3	3.5	V	V_{DS}=V_{GS}, I_D=0.66 mA
Zero gate voltage drain current	I_{DSS}	- -	- 10	1 -	µA	V_{DS}=600 V, V_{GS}=0 V, T_j=25 °C V_{DS}=600 V, V_{GS}=0 V, T_j=150 °C
Gate-source leakage curent	I_{GSS}	-	-	100	nA	V_{GS}=20 V, V_{DS}=0 V
Drain-source on-state resistance	$R_{DS(on)}$	- -	0.18 0.47	0.199 -	Ω	V_{GS}=10 V, I_D=9.9A, T_j=25 °C V_{GS}=10 V, I_D=9.9 A, T_j=150 °C
Gate resistance	R_G	-	2	-	Ω	f=1 MHz, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	1520	-	pF	V_{GS}=0 V, V_{DS}=100 V, f=1 MHz
Output capacitance	C_{oss}	-	72	-	pF	V_{GS}=0 V, V_{DS}=100 V, f=1 MHz
Effective output capacitance, energy related[1]	$C_{o(er)}$	-	69	-	pF	V_{GS}=0 V, V_{DS}=0...480V
Effective output capacitance, time related[2]	$C_{o(tr)}$	-	180	-	pF	I_D=constant, V_{GS}=0 V, V_{DS}=0...480V
Turn-on delay time	$t_{d(on)}$	-	10	-	ns	V_{DD}=400 V, V_{GS}=13 V, I_D=9.9 A, R_G=3.3Ω; see table 9
Rise time	t_r	-	5	-	ns	V_{DD}=400 V, V_{GS}=13 V, I_D=9.9 A, R_G=3.3Ω; see table 9
Turn-off delay time	$t_{d(off)}$	-	50	-	ns	V_{DD}=400 V, V_{GS}=13 V, I_D=9.9 A, R_G=3.3Ω; see table 9
Fall time	t_f	-	5	-	ns	V_{DD}=400 V, V_{GS}=13 V, I_D=9.9 A, R_G=3.3Ω; see table 9

Table 6 Gate charge characteristics

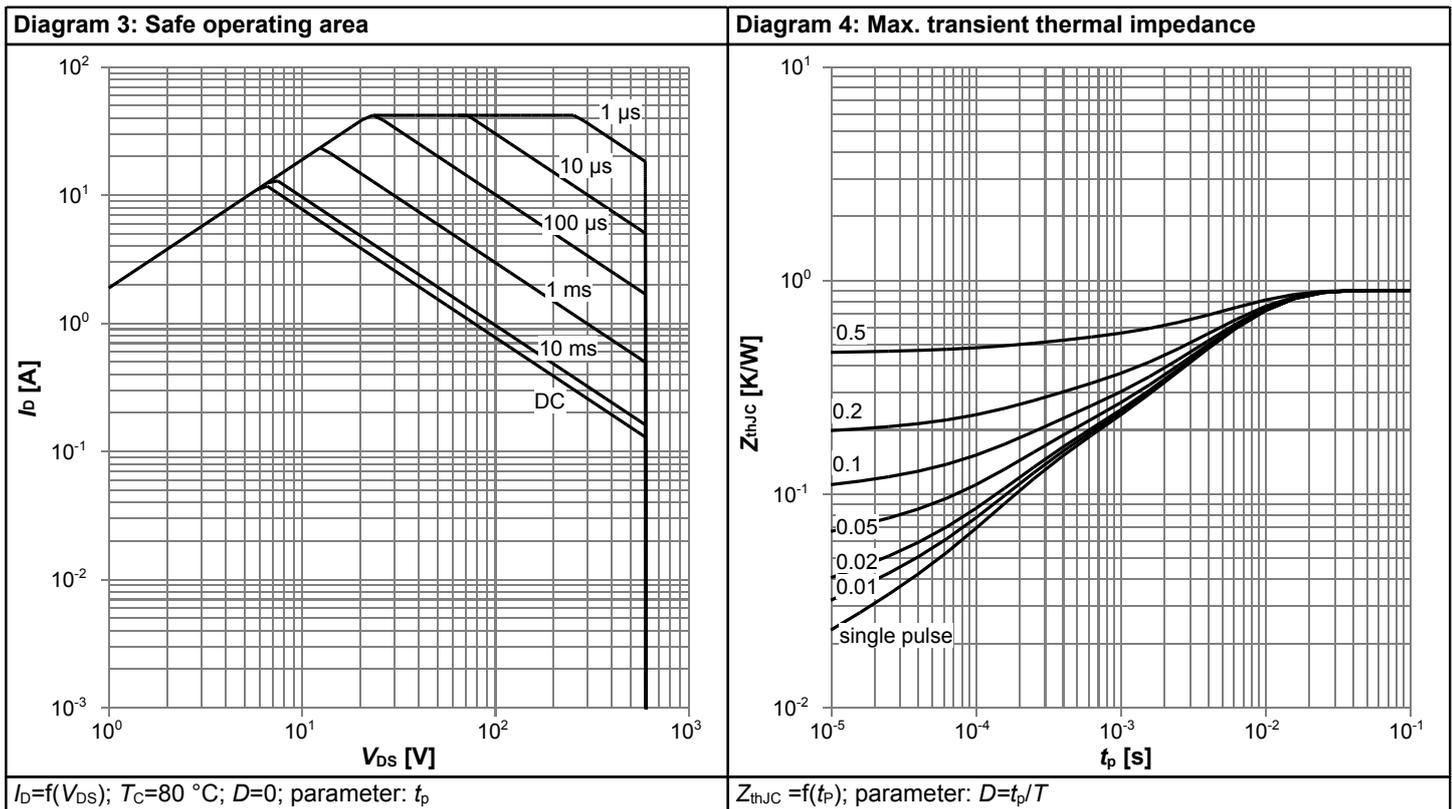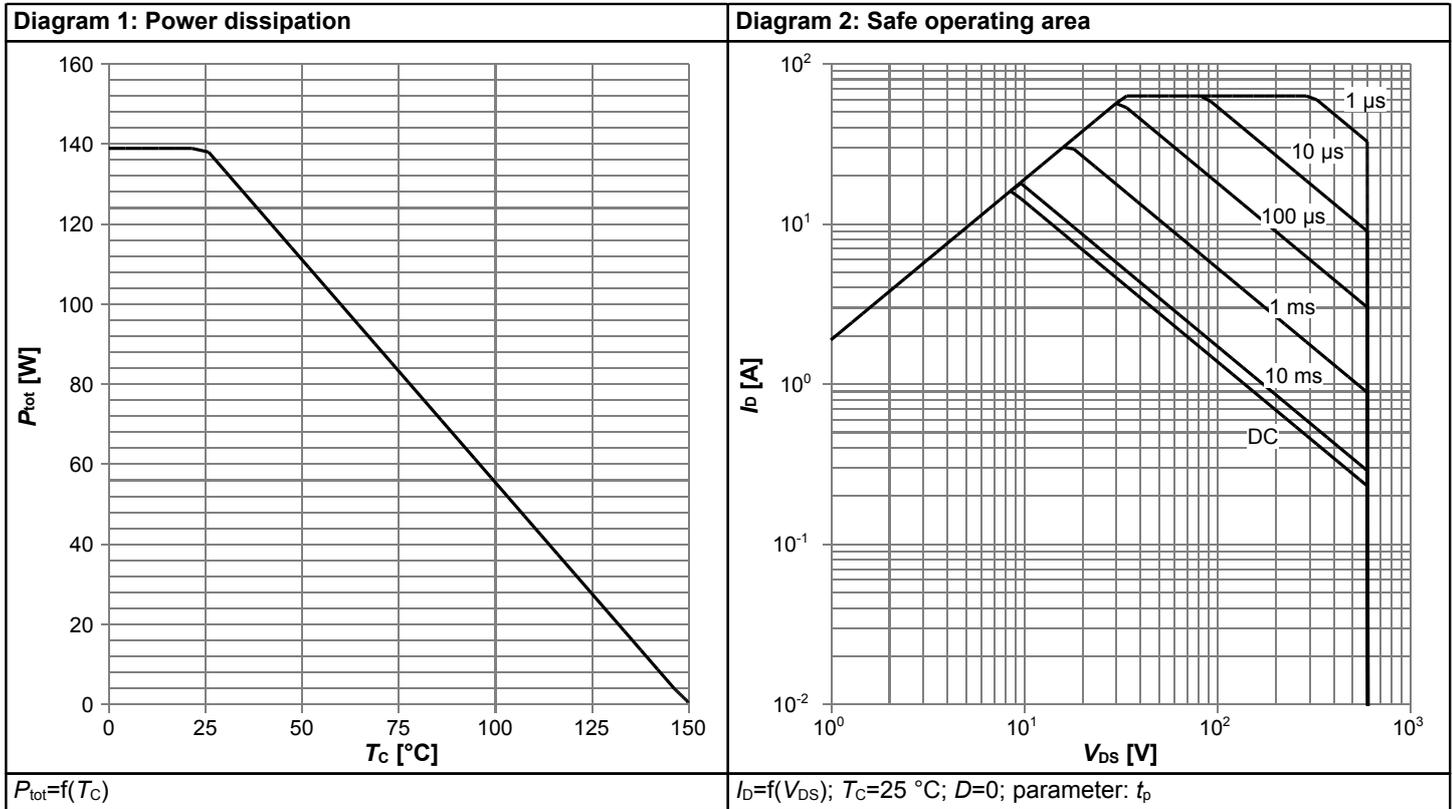| Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	8	-	nC	V_{DD}=480 V, I_D=9.9 A, V_{GS}=0 to 10 V
Gate to drain charge	Q_{gd}	-	11	-	nC	V_{DD}=480 V, I_D=9.9 A, V_{GS}=0 to 10 V
Gate charge total	Q_g	-	32	-	nC	V_{DD}=480 V, I_D=9.9 A, V_{GS}=0 to 10 V
Gate plateau voltage	$V_{plateau}$	-	5.0	-	V	V_{DD}=480 V, I_D=9.9 A, V_{GS}=0 to 10 V

[1] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$
[2] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$

Table 7   Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.9	-	V	V_{GS}=0 V, I_F=9.9 A, T_j=25 °C
Reverse recovery time	t_{rr}	-	340	-	ns	V_R=400 V, I_F=9.9 di_F/dt=100 A/µs see table 8
Reverse recovery charge	Q_{rr}	-	5.5	-	µC	V_R=400 V, I_F=9.9 di_F/dt=100 A/µs see table 8
Peak reverse recovery current	I_{rrm}	-	33	-	A	V_R=400 V, I_F=9.9 di_F/dt=100 A/µs see table 8

4 Electrical characteristics diagrams

Diagram 1: Power dissipation

P_{tot}=f(T_C)

Diagram 2: Safe operating area

I_D=f(V_{DS}); T_C=25 °C; D=0; parameter: t_p

Diagram 3: Safe operating area

I_D=f(V_{DS}); T_C=80 °C; D=0; parameter: t_p

Diagram 4: Max. transient thermal impedance

Z_{thJC} =f(t_P); parameter: D=t_p/T

Diagram 5: Typ. output characteristics
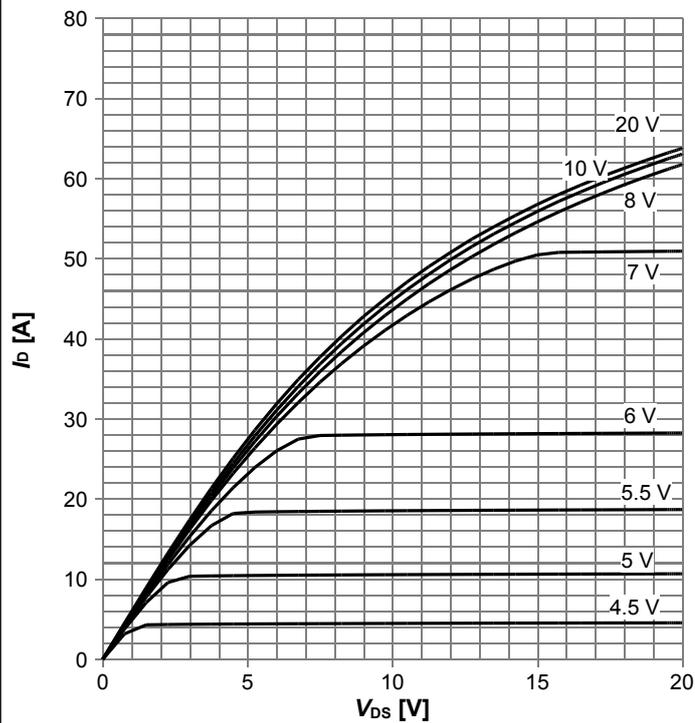
I_D=f(V_{DS}); T_j=25 °C; parameter: V_{GS}

Diagram 6: Typ. output characteristics
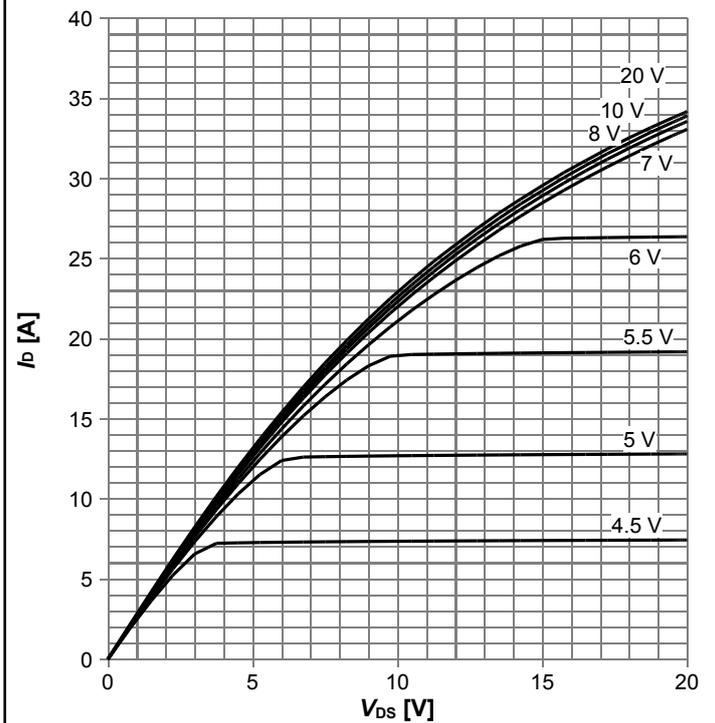
I_D=f(V_{DS}); T_j=125 °C; parameter: V_{GS}

Diagram 7: Typ. drain-source on-state resistance
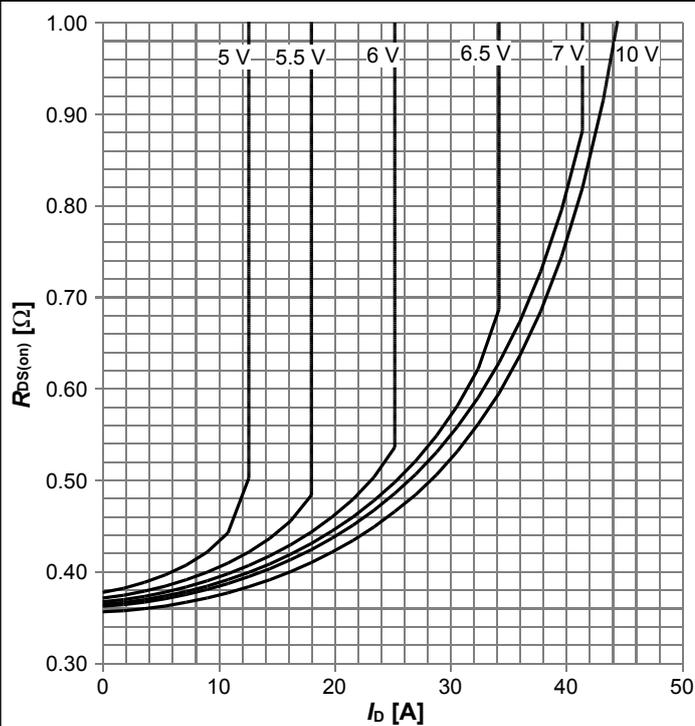
$R_{DS(on)}$=f(I_D); T_j=125 °C; parameter: V_{GS}

Diagram 8: Drain-source on-state resistance
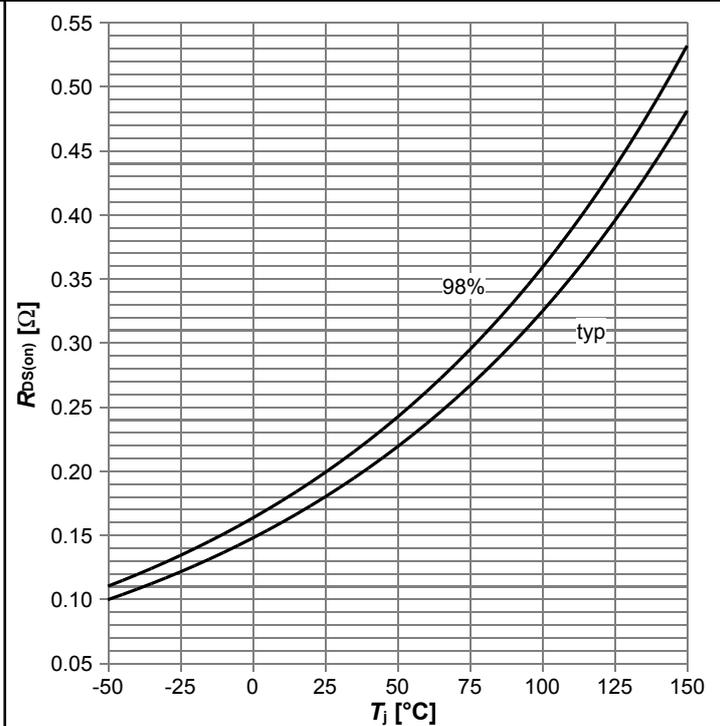
$R_{DS(on)}$=f(T_j); I_D=9.9 A; V_{GS}=10 V

Diagram 9: Typ. transfer characteristics
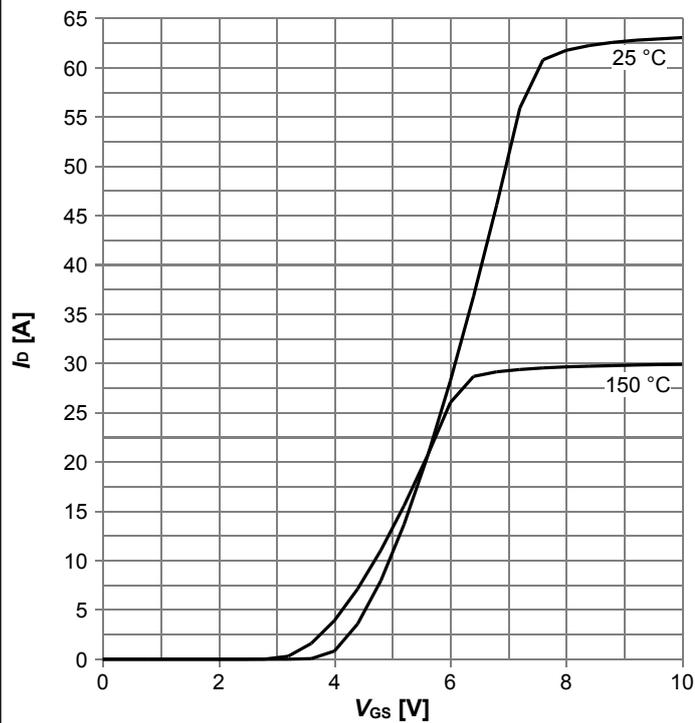
I_D=f(V_{GS}); V_{DS}=20V; parameter: T_j

Diagram 10: Typ. gate charge
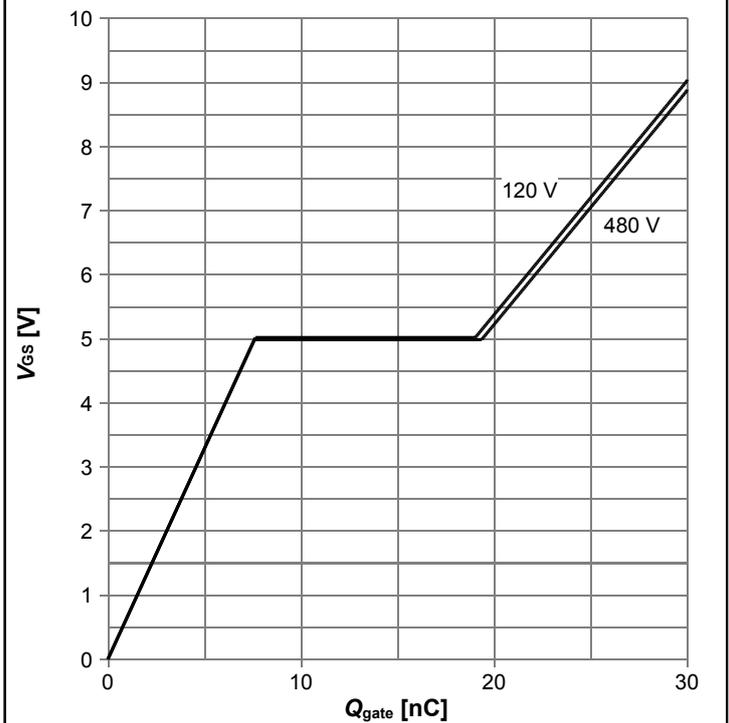
V_{GS}=f(Q_{gate}); I_D=9.9 A pulsed; parameter: V_{DD}

Diagram 11: Forward characteristics of reverse diode
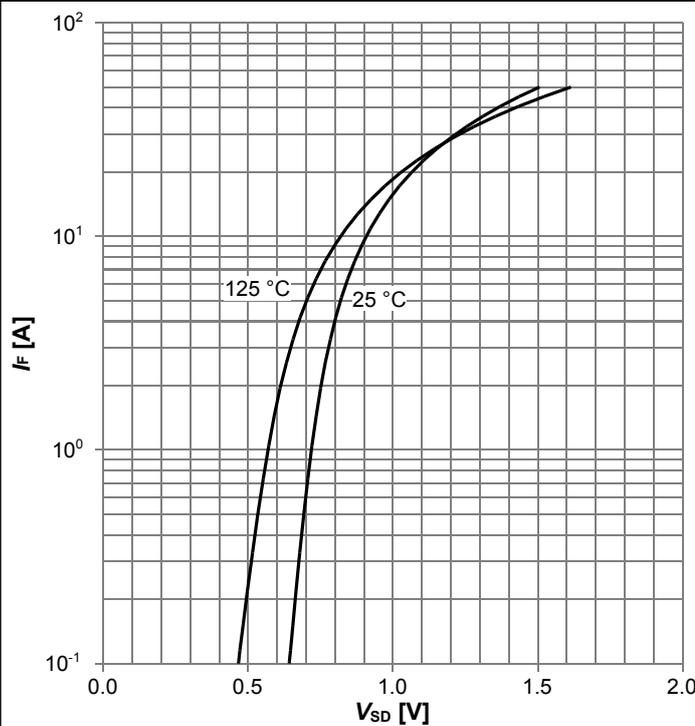
I_F=f(V_{SD}); parameter: T_j

Diagram 12: Avalanche energy
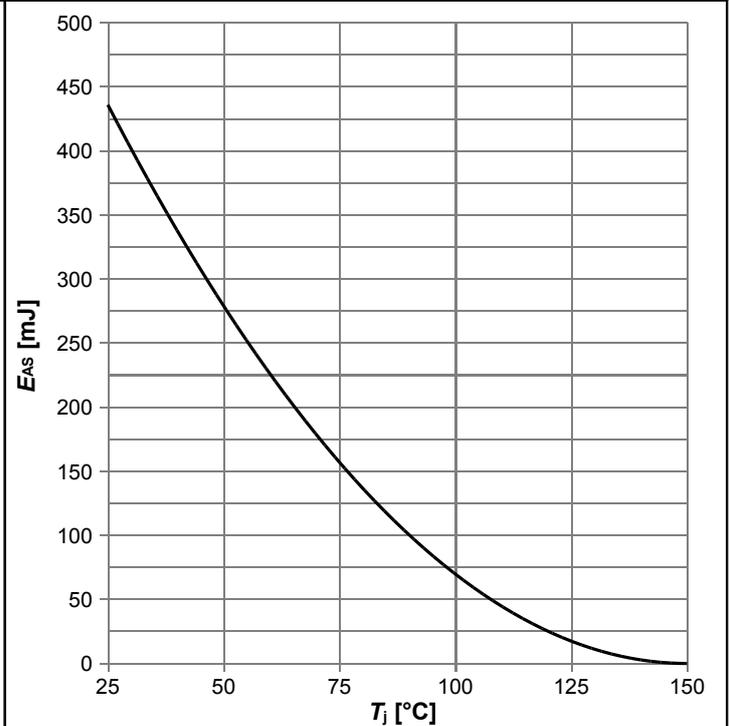
E_{AS}=f(T_j); I_D=6.6 A; V_{DD}=50 V

Diagram 13: Drain-source breakdown voltage
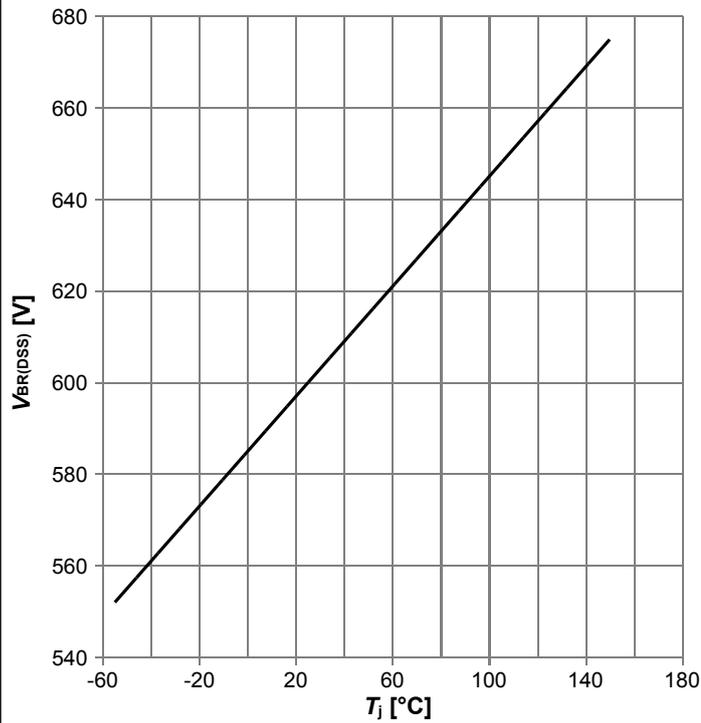
$V_{BR(DSS)}$=f(T_j); I_D=0.25 mA

Diagram 14: Typ. capacitances
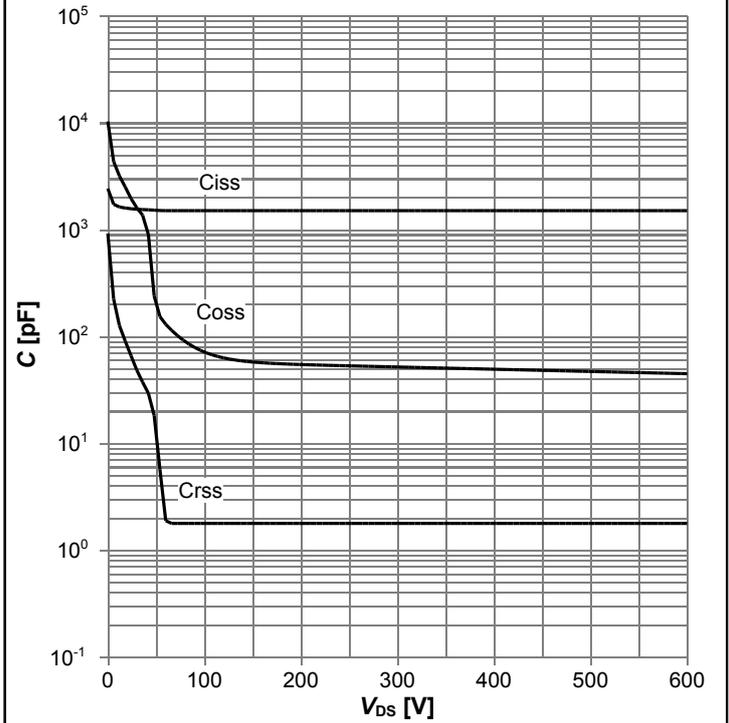
C=f(V_{DS}); V_{GS}=0 V; f=1 MHz

Diagram 15: Typ. Coss stored energy
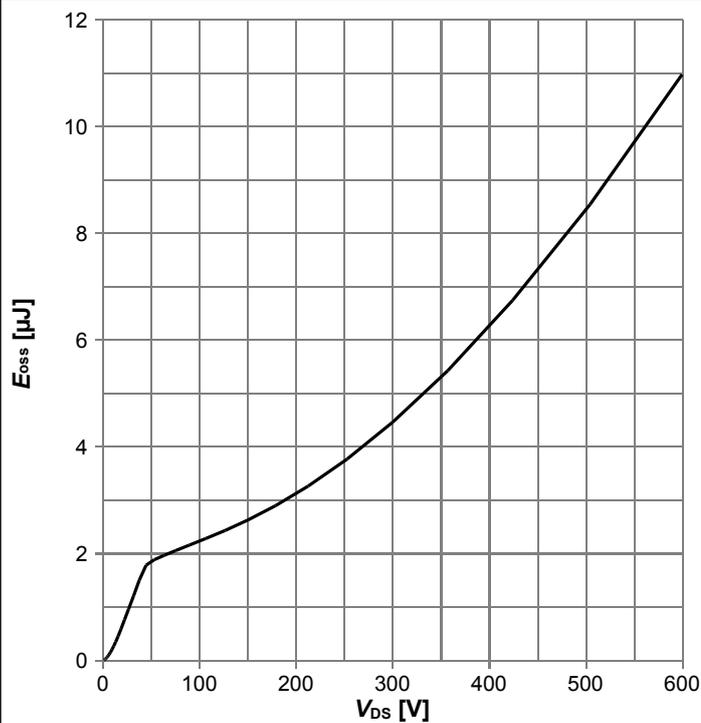
E_{oss}=f(V_{DS})

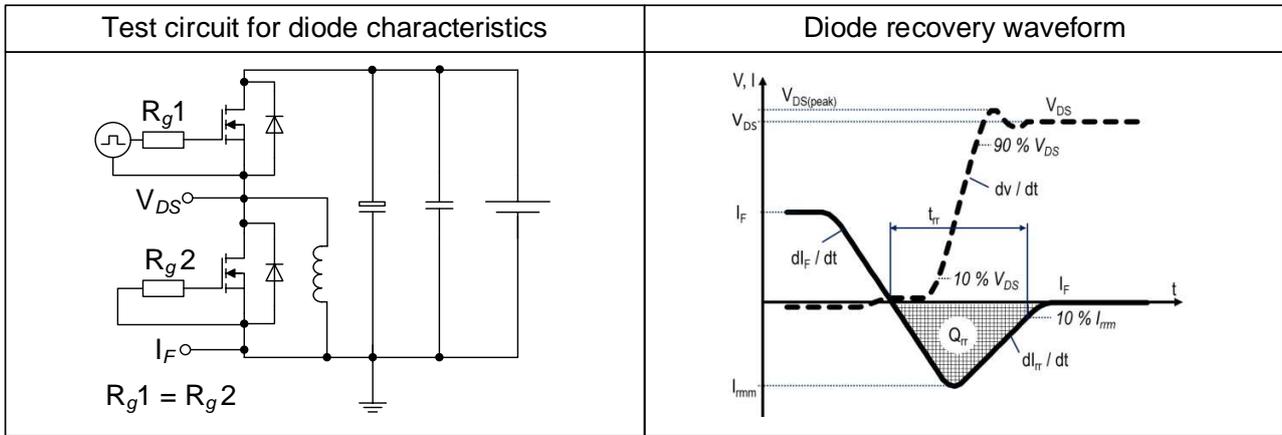# 5 Test Circuits

Table 8 Diode characteristics

Test circuit for diode characteristics	Diode recovery waveform

Table 9 switching times (ss)

Switching times test circuit for inductive load	Switching times waveform
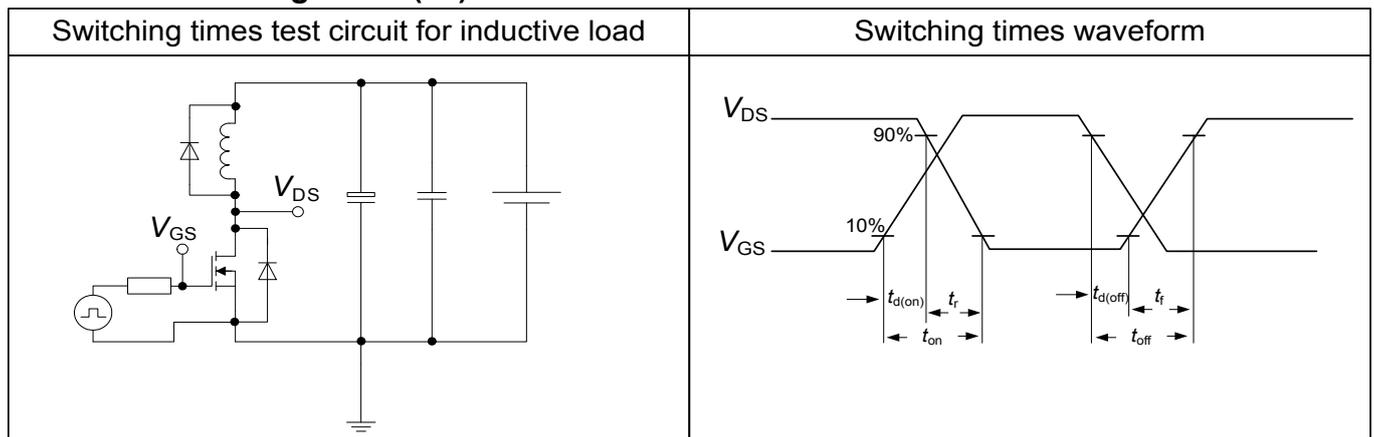
Table 10 Unclamped inductive load (ss)

Unclamped inductive load test circuit	Unclamped inductive waveform

6   Package Outlines

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.90	1.10	0.035	0.043
b	0.90	1.10	0.035	0.043
b1	0.00	0.05	0.000	0.002
c	0.10	0.30	0.004	0.012
D	7.90	8.10	0.311	0.319
D1	7.10	7.30	0.280	0.287
E	7.90	8.10	0.311	0.319
E1	4.65	4.85	0.183	0.191
E2	2.65	2.85	0.104	0.112
E3	0.30	0.50	0.012	0.020
e	2.00 (BSC)		0.079 (BSC)	
L	0.40	0.60	0.016	0.024
N	4		4	
F1	7.20		0.283	
F2	4.75		0.187	
F3	1.00		0.039	
F4	1.00		0.039	
F5	1.43		0.056	
F6	4.20		0.165	
F7	3.00		0.118	
F8	1.00		0.039	

DOCUMENT NO.
Z8B00156707

SCALE

EUROPEAN PROJECTION

ISSUE DATE
05-04-2010

REVISION
01

Figure 1   Outline PG-VSON-4, dimensions in mm/inches

7   Appendix A

Table 11   Related Links

- **IFX CoolMOS Webpage:** www.infineon.com

- **IFX Design tools:** www.infineon.com

Revision History

IPL60R199CP

Revision: 2017-09-06, Rev. 2.4

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.3	2015-10-23	Update of ID pulse according to SOA Diagram on page 2 and 3
2.4	2017-09-06	Updated MSL; style updated

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